Valve Electronic CV3930

SPECIFICATION MOS/CV.3930 incorporating MIL-E-1/172B.	SECURITY				
ISSUE No. 1. DATED 1.2.58.	SPECIFICATION	<u>VALVE</u>			
To be read in conjunction with Kloo6 and BS.448.	Unclassified	Unclassified			

TIPE OF VALVE:- Sub-miniature Triode Oscillator with flying leads.					MARKING						
CATHOLE: Indirectly heated.					See K1001/4.						
ENVELOFE: - Glass.					Additional Marking 5718.						
PROTOTYPE:											
	RATINGS			BASE							
(All limit	ing values are abso	İ	BS.448/B8D/F.								
		(v)		NOTES	ļ						
Heater Volts Heater Current Max. Operating Another	6.3 150 165		CONNEC TORS								
Max. Anode Dissipat Max. Negative Grid	0.9 55		PIN	EL	LECTRODE						
Max. Negative Grid Voltage Max. Anode Current Max. Reater Cathode Voltage Max. Bulb Temperature Typical Operating Conditions Anode Voltage Anode Current Mutual Conductance Amplification Factor (ma/V)					12345678	Grid No connec Heater No connec Cathode Heater No connec Anode	tion	g h k h			
	ANCES(DF) NOTE A				DIMENSIONS(mm)						
Cag (nom.) Cin (nom.) Cout (nom.)			1.45 2.2 0.7			ENSIONS ated Height	<u>жт</u> . 9•3	<u>MAX</u> . 34.92 10.16			
		NOTES	3								
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MIL-E-1/172B 5 August 1955 SUPERSEDING MIL-E-1/172A 26 October 1954

INDIVIDUAL MILITARY SPECIFICATION SHEET

ELECTRON TUBE, RECEIVING, TRIODE. SUBMINIATURE

JAN-5718

This specification sheet forms a part of the latest issue of military Specification MIL-E-1.

Description: Triode, 500 Mc, Medium Mu

Ratings: Absolute Maximum:	Ef V 6.6	Eb Vdc 165	Ec Vdc O	Ehk ▼ 200	Rk ohms	Rg Meg 1.2	Ib māde 22.0	Ic mAdc 5.5	Pp W 0.9	T Envelope °C +220	Alt ft 60,000
Miņimum:	6.0		-55								Note 2
Test Cond.:	6.3	100	0	0 Note 1	150 Note 1						

Cathode: Coated Unipotential
Base: Subminiature-8 Pin with long leads

Diameter: 0.400 in. max. Height: 1.375 in. max.

Envelope: T-3

Ref.	llaneous requirements, see Par Test	Conditions	AQL(%)	Insp. Level	Syma.							
		CORT FIORB		Code	Sym.	Kin.	LAL	Bogie		Max.	ALD	Units
	Qualification (pproval Tes	ta										
3.1	Qualification Approval:	Required for JAN Marking										
	Cathode:	Coated Unipotential										
3.4.3	Base Connections:		-	_								
	Measurements Acceptance Tests, Part 1, Note 3											
4.10.8	Heater Current:	Note 4			If:		144	150	156		12	* →
4.10.8	Heater Current:		0.65	II	If:	140	_	_	_	160		mA.
4.10.15	Heater-Cathode Leakage:	Ehk=+100Vdc Ehk=-100Vdc	0.65	11	Ihk: Ihk:	_	=	=	_	5 5	_	uAdc uAdc
.10.6.1	Grid Current:	Eb=150Vdc;Rk=380; Rg=1.0Meg	0.65	п	Ica	ο,				-0.4	_	uAdc
4.10.4.1	Plate Current(1):	Note 4			Ibs	_	7.5	8.5	9-5		3.0	mAdc .
4.10.4.1	Plate Current(1):		0.65	II	Ibs	6.0			<u> </u>	11.0	_	mA dc
4.10.4.1	Plate Current(2):	Ec=-7.0Vdc; Rk=0	0.65	11	Ib:	_		-		100	_	uAdc -
4.10.9	Transconductance(1):	Note 4			Sas		5400	5800	6200		1150	umhos
4.10.9	Transconductance(1):		0.65	II	Sear	4800				6800	-	umhos
4.7.5	Continuity and Shorts (Inoperatives):		0.4	II	-	_		_	-	_		
4.9.1	Mechanical:	Envelope (8-1)										
	Measurements Acceptance Tests, Part 2											
4.8.2	Insulation of Electrodes:	g-all p-all	2.5	I	Ra Ra	100 100	=	=	=	=	_	Mog Mog
4.10.4.1	Plate Current(3):	Ec=-4.0Vde; Rk=0	2.5	I	Ib:	20	-			-		uAdo.
.10.9	Transconductance(2):	Ef=5.7V; Note 22	2.5	I	∆ _{Ef} :					10	_	\$:
.10.6.2	Grid Baission:	Ef=7,.5V;Ec=-7.0Vdc; Rg=1.0Meg;Note 23	2.5	I	Ica	0		_	_	-0.4	_	nAdc

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Ref.	Test	Conditions	AQL(%)	Insp. Level or Code	Зув.	Min.	ALD	Units						
	Measurements Acceptance	Tests Part 2(Contd)						-						
4.10.3.2	AF Noise:	Esig=50mVac;Ec=-4.0Vdc; Rk=0;Rg=0.1Meg;Rp=0.01 Meg	2.5	1	23 :			-		17	_	v u		
4.10.11.1	Amplification Factor:		6.5	14	Mu	23			_	31				
4.10.2.2	Power Oscillation:	F=500Me;Eb=150Vde; Rg/Ib=20mAde	6.5	14	Po:	600			_	-		18		
4.10.14	Capacitance:	No Shield No Shield No Shield	6.5	Code	Cgp: Cin: Cout:	1.1 1.6 0.5	=	=	=	1.8 2.8 0.9		uul uul uul		
	Low Pressure Voltage Breakdown:	Pressure=55+5mm Hg.; Voltage=300Vac;Note 6	6.5	Note 5			-	_	—					
4.9.20.3	Vibration(1):	No Voltages; Post Shock and Fatigue Test End Points apply	10.0	Note 5			_	-		-				
4.9.19.1	Vibration(2):	Rp=10,000; Ck=1000uf; F=40cps; G=15; Note 7	2.5	1	Ep:				_	25	-	mVac		
	Degradation Rate Accepta	nce Tests Note 8						•						
4-9-5-3	Subministure Lead Futigue:	Note 9	2.5	Çode F		4	-	_	-	-	_	arcs		
4.9.20.5	Shock:	Hammer angle=30°; Ehk=+100Vdc;Rg=0.1Meg; Note 10	20		_		-	_		-	_			
4.9.20.6	Fatigue:	G=2.5; Fixed Prequency; F=25min., 60max.	6.5	Note 5	-				-		_			
	Post Shock and Fatigue Test End Points:	Vibration(2) Heater-Cathode Leakage Ehk=+100Vdc Ehk=-100Vdc Change in Transconductance(1) of individual tubes	=	=	Ep: Ihk: Ihk: ASm:	=	=	=	=	100 15 15 15	1 111	mVac uAdc uAdc ≸		
	Glass Strain:	Note 11	6.5	ı			_		_	_	_			
Ref.	Test	Conditions ·			Characteristic 1st Combined		per aracteristic Combined		per aracteristic Sym Combined		Sym.	LIM Min.	TS Max.	Units
	Acceptance Life Tests No	te 8												
4.11.7	Heater Cycling Life Test:	Ef=7.0V; 1 min. on, 4 min. off; Ehk=140Vac; Ec=Eb=0; Note 12	2.5	Code H	-		_	ł	-	_	-			
	Stability Life Test: (1 Hour)	Ehk=+200Vdc; Rg=1.0Meg; TA=Room; Note 13	1.0	Code					-		_			
4.11.4	Stability Life Test End Points:	Change in Transconduc- tance(1) of individual tubes	-		_				Δ <mark>3.</mark> :	_	10	\$		
-	Survival Rate Life Test:	Stability Life Test Conditions or equivalent; TA=Room; Notes 14,15	-	11		.			_	-	_			
4.11.4	Survival Rate Life Test End Points:	Continuity_and Shorts (Inoperatives) Transconductance(1)	0.65	_	_ _				 Sm:	4500	_	umhos		
1 1			1	L	L					L	i	l		

Ref.	Test	Conditions	AQL(%)	Insp. Level or		e Defectives per teristic	Sym.	LIMITS		Units
				Code	lst Sample	Combined Semples		Min.	Max.	
	Acceptance Life Tests(Co	ntd)								
4.11.5	Intermittent Life Test:	Stability Life Test Conditions; T Envelope= +220°C min; Notes 16,17; 1000 hour requirements do not apply						-	-	
4.11.4	Intermittent Life Test End Points; (500 Hours): Note 16	Note 18 Inoporatives; Note 19 Grid Current Heater Current Change in Transconduc- tance(1) of individual tubes	=	=	1 1 2 1	3 3 5 3	Ic: If: A:	0 138	-0.6 164 20	ukdo må \$
		Transconductance(2) Heater-Cathode Leakage	_	-	2	5	Δ Sm .	-	15	\$
•		Ehk=+100Vdc Ehk=-100Vdc Insulation of Electrodes	_	-	2	5	Ihk: Ihk:	=	10 10	uAde uAde
		g-all p-all	—		2	5	R: R:	50 50	_	Meg Meg
		Transconductance(1) average change					Avg•∆Şm;		15	*
		Total Defectives	_	-	4	8		-	-	
4.11.5	Information Life Test: (1000 Hours)	Intermittent Life Test Conditions; Notes 17,20, 21								
	Packaging Information									
4.9.18.1.1	Carton Drop:	(d) Package Group 1; Carton Size C								

Caution to Electron Equipment Design Engineers. Special attention should be given to the temperature at which the tubes are to be operated. Reliability will be seriously impaired if maximum bulb temperature is exceeded. The life expectancy may be reduced if conditions other than those specified for life test are imposed on the tube and will be reduced appreciably if absolute maximum ratings are exceeded. Both reliability and performance will be jeopardized if filament voltage ratings are exceeded. Life and reliability of performance are directly related to the degree that regulation of the heater voltage is maintained at its center rated value.

- Note 1: The reference point for heater-cathode potential shall be the positive terminal of the cathode resistor, unless otherwise specified.
- Note 2: If altitude rating is exceeded, reduction of instantaneous voltages (Mf, excluded) may be required.
- Note 3: The ACL for the combined defectives for attributes in Measurements Acceptance Tests, Part 1, excluding inoperatives and mechanical shall be one (1) percent. A tube having one (1) or more defects shall be counted as one (1) defective. MIL-STD-105, Inspection Level II shall apply.
- Note 4: Variables Sampling Procedure:

Test for Lot-Average Acceptance:

Select a 35 tube sample at random from the lot. Sumber these tubes consecutively.

Determine the numerical average value of the characteristic as specified on the specification sheet of the 35 tube sample. If this value is on or above the LAL and on or below the UAL, accept for Lot Average.

Test for Lot Dispersion Acceptance:

Divide the 35 tube sample into seven (7) consecutive sub-groups of five (5) tubes each. Determine the range, R, of each sub-group for the measured characteristic specified on the Specification Sheet.

Compute the numerical average of the R values which is equal to \overline{R} . If \overline{R} is equal to or less than the ALD, accept for Lot Dispersion.

- Note 5: This test shall be conducted on the initial lot and thereafter on a lot approximately every 30 days. Once a lot has passed, the 30-day rule shall apply. In the event of lot failure, the lot shall be rejected and the succeeding lot shall be subjected to this test. MIL-STD-105, sample size code letter F shall apply.
- Note 6: There shall be no evidence of arcing or corona between anode pins and adjacent pins with no other voltages applied.

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- For vibration tests, the impedance of the plate voltage supply shall not exceed that of a 40 uf capacitor at 10 cps.
- Rote 8: Destructive tests:

Tubes subjected to the following destructive tests are not to be accepted under this specification

- Subminiature Lead Fatigue. Shock. Fatigue.
- 4.9.20.5
- 4.11.7 Heater Cycling Life Test. Intermittent Life Test.
- When a manufacturer submits tubes for qualification approval, five extra tubes shall be submitted for lead fatigue testing. These may be electrical rejects. Note 9:
- Note 10: Leads may be clipped for application of voltages during impact.
- Class strain procedures All tubes submitted to this shall have been sealed a minimum of 48 hours prior to conducting this test. All tubes shall be at room temperature. The entire tube shall be immersed in water not less than 85°C for 15 seconds and immediately thereafter immersed in water not more than 5°C for 5 seconds. The volume of water shall be large enough that the temperature will not be appreciably affected by the test. The method of submersion shall be in accordance with Drawing #245 JAM, and such that a minimum of heat is conducted away by the holder used. The tubes shall be placed in the water so that no contact is made with the containing vessel, nor shall the tubes contact each other. After the 5-second submersion period, the tubes shall be removed and allowed to dry at room temperature on a wooden surface. After drying at room temperature for a period of 48 hours, the tubes shall be inspected and rejected for evidence of air leaks. Electrical rejects other than inoperatives may be used in the performance of this test. Note 11:
- The regulation of the heater voltage supply shall be not more than 3.0 percent. This test shall be made on a lot by lot basis. A failure or defect shall consist of an open heater, open cathode circuit, or a heater-cathode short.

Note 13: Stability Life Test:

- Life test samples shall be selected from a lot at random in such a manner as to be representative of the lot. If such selection results in a sample containing tubes which are outside the initial specification sheet limits for the relevant life test end point characteristics, such tubes shall be replaced by randomly selected acceptable tubes.
- Serially mark all tubes from the sample.
- Record referenced characteristic measurements after a maximum operation of 15 minutes at specified voltage and current conditions on the entire sample.
- d. Operate at life test conditions for one (1) hour (plus 30 minutes, minus 0 minutes). Life test shall be conducted as per paragraphs 4.11 and 4.11.5, MIL-E-1, except that the following shall be substituted for the third sentence of 4.11: The mean electrode potentials, except heater or filament, may be established at values differing by not more than 5% from the specified values provided the same average electrode dissipations are obtained that occur with the specified voltages. Fluctuations of all voltages including heater or filament voltage shall be as small as practical.
- Record referenced characteristic measurements at the end of this test period. Referenced characteristic measurements shall be taken immediately following the test or tubes shall be preheated 15 minutes under specified test voltage and current conditions, and immediately measured. The 15 minutes preheat shall be considered as part of the test time.
- f. A defective shall be defined as a tube having a change in referenced characteristic greater than that specified on the specification sheet.
- A resubmitted lot must be subjected to all Measurements Acceptance Tests except Mechanical Inspection, Vibration, and Low Pressure Voltage Breakdown tests.
- MEANS OF ASSURING SURVIVAL RATE The procedure for assuring the maintenance of a desirable quality level in terms of early life survival consists of a series of normal, reduced, and tightened inspection plans for use at 100 hours. The sample size is dependent upon tot size, and the transfer between normal, reduced, and tightened inspection is dependent upon quality history. Note 14:

The selection of inspection scheme and sampling plan shall be in accordance with Inspection Instructions for Electron Tubes paragraph 5.3.4.2 through 5.3.4.3.1.3 inclusive except that paragraph 5.3.4.2.2 shall be modified by deleting the last part of the first sentence which states...or if no lot in the last 20 lots inspected shall have been declared nonconforming for life test qualities. At the manufacturer's option, reduced inspection may be used if no lot in the last ten (10) lots inspected have been declared nonconforming

INSPECTION PROCEDURE

- Select sample in accordance with Note 13, paragraph (a).
- Tubes to be tested at 100 hours as provided in MIL-E-1(4.7.5). When any tap-short indication is obtained, the test shall be repeated. When any short indication is again obtained the tube will be rejected as an inoperative.
- Determine the number of defective tubes at the 100 hour period.

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- Note 14: (Contd) d. If more than the allowable number of defectives occur, declare the lot nonconforming.
 - A resubmitted lot must be subjected to all Measurements Acceptance Tests except Mechanical Inspection, Vibration, and Low Pressure Voltage Breakdown tests.
- Note 15: For Survival Kate Life Test, the equivalent Stability Life Test conditions shall be interpreted as having the same heater voltage (Ef) and heater-cathode voltage (Ehk) as the Stability Life Test; and the same interruptions of MIL-E-1 paragraph 4.11.5 as the Intermittent Life Test. The electrode voltages shall be such that the element dissipations are not less than 80 percent, nor zore than 100 percent of Stability Life Test Plate Dissipation.

 These voltages are to be maintained within the limits of plus 200, minus 50 percent of the Stability Life Test

Intermittent Life Tests:

- The first 20 tubes of the Stability Life Test sample which meet the measurements acceptance test limits for those characteristics specified as Intermittent Life Test End Points shall be used for the Intermittent Life Test sample. In the event that a second Stability Life Test sample is used, the first 20 tubes from that sample which meet the above conditions shall be used.
- In the event of failure of the first sample on Intermittent Life Test, take a completely fresh sample(MIL-STD-105 sample size code letter I) and stabilize it in accordance with the conditions of the Stability Life Test. Then select from it the first 40 tubes which meet the measurements acceptance test limits for those characteristics specified as Intermittent Life Test End Points.

 Subject these 40 tubes to the Intermittent Life Test. Acceptance shall then be based on combined results from the first and second samples.

- as an alternate method, the manufacturer may select his life test sample as described in Note 13, paragraph (a).
- d. Life test shall be conducted as per paragraphs 4.11, and 4.11.5, MIL-E-1, except that the following shall be substituted for the third sentence of 4.11: The mean electrode potentials, except heater or filament may be established at values differing by not more than 5% from the specified values provided the same average electrode dissipations are obtained that occur with the specified voltages. Fluctuations of all voltages including heater or filament voltage shall be as small as practical.
- Regular Life Test
 - 1. Regular Life test shall be conducted for 1000 hours.
 - 2. Regular life test acceptance shall be on the basis of the 500 and 1000 hours requirements as indicated
 - Regular life test shall be in effect initially and shall continue in effect until the eligibility criteri.
 for the Reduced Hours Life Test have been met.
- f. Reduced Hours Life Tests
 - 1. Reduced Hours Life Test shall be conducted for 500 hours and acceptance shall be based on the 500 hour end point limits.
 - Eligibility for Reduced Hours Life Tests: No lot failure due to the 1000 hour life test has occurred in the preceding three(3) consecutive lots.
 - Loss of eligibility for Reduced Hours Life Test: Two (2) or more 500 hour life test lot failures occurring in the last three (3) consecutive lots.
- o. The life test sample shall be read at the following times:

0 hours 500 hours (plus 48 hours; minus 24 hours) 1000 hours (plus 48 hours; minus 24 hours; when in force)

additional reading periods may be used at the discretion of the electron tube manufacturer.

- Acceptance Criterias The lot shall be considered satisfactory for acceptance provided that the specified allowable defects are not exceeded and the change of the average of any characteristic in the life test sample specified for life test control of averages is not exceeded. The average percentage change shall be sacertained from the determination of the individual changes for each tube in the life test sample from the zero (0) hour value for the referenced characteristic or characteristics. For purposes of computation of this average percentag change, the absolute values of the individual changes for each tube in the life test sample shall be used. Any tube found inoperative during life testing shall not be considered in the calculation of this average.
- A resubmitted lot must be subjected to all Measurements accepts on Tests except Leonardcal Inspection, Vibration, and Low Pressure Voltage Breakdown.
- Not rore than one (1) accidental breakage shall be allowed in the life test sample. In the event that one (1) life test tube is accidentally broken, acceptability of the life test sample shall be based upon the remaining tubes in the sample provided that the broken tube was not known to be a defective.
- Envelope Temperature is defined as the highest temperature indicated when using a thermocourie of #40 B5 or smaller diameter elements melded to a ring of .025 inch diameter phosphor bronze of ced in contact with the envelope. Note 17:
- Order for evaluation of life test defects.- In the event that a tube le defective for more than one a teristic, the characteristic appearing first in the Life Test and Points shall constitute the failure. Note 18:
- An inoperative as referenced in Life Test is defined as a tube having one (1) or nore of the following defects: Aiscontinuity (Ref. mIL-5-1, par. 4.7.1), shorts (Ref. mIL-5-1, par. 4.7.2), air leaks. Note 19:

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- Note 20: On Information Life Tests, read same characteristics as Intermittent Life Test. Limits do not apply. Six copies of these data shall be forwarded to the Armed Services Electron Tube Committee upon request.
- Note 21: This life test shall be conducted on a minimum of one sample of ten tubes each month of production. This sample shall be selected as the first ten serially marked, noninoperative tubes from a completed Intermittent Life Test sample. This life test shall be classified as a destructive test. Read at 1000 hours.
- Note 22: Transconductance (2) is the percent change in Transconductance (1) of an individual tube resulting from the change in Rf.
- Note 23: Prior to this test tubes shall be preheated 5 minutes at conditions indicated below. Test within three (3) seconds after preheating. Three-minute test is not permitted. Grid Emission shall be the last test performed on the sample selected for the Grid Emission test.

Ro ### Rk Rg
Vdc Vdc ohms Meg
###7.5 0 100 150 1.0

Note 24: Reference specification shall be of the issue in effect on the date of invitation for bid.

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